

## FNK N-Channel Enhancement Mode Power MOSFET

## **Description**

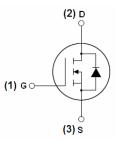
The FNK03N06F uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

- $V_{DS}$  =30V, $I_{D}$  =80A R DS(ON) <7.0m  $\Omega$  @  $V_{GS}$ =10V R DS(ON) <12m $\Omega$ @  $V_{GS}$  =4.5V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

## **Application**

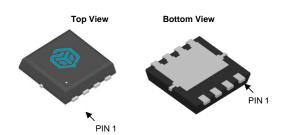
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



#### Schematic diagram



Marking and pin assignment



#### **Package Marking and Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
03N06F	FNK03N06F	DFN3.3*3.3	-	-	-

## Absolute Maximum Ratings (T<sub>A</sub>=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	30	V	
Gate-Source Voltage	V <sub>GS</sub>	±20	V	
Drain Current-Continuous	I <sub>D</sub>	80	Α	
Drain Current-Continuous(T <sub>C</sub> =100°C)	I <sub>D</sub> (100℃)	50	Α	
Pulsed Drain Current	I <sub>DM</sub>	320	Α	
Maximum Power Dissipation	P <sub>D</sub>	100	W	
Derating factor		0.56	W/℃	
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	150	mJ	
Operating Junction and Storage Temperature Range	$T_{J}, T_{STG}$	-55 To 175	$^{\circ}\!\mathbb{C}$	



# FNK03N06F

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	$R_{ heta JC}$	1.5	°C/W
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## Electrical Characteristics (T<sub>A</sub>=25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics			•	•		•
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	30	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μΑ
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20 $V$ , $V_{DS}$ =0 $V$	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS},I_{D}=250\mu A$	0.85		1.35	V
Drain Course On State Desintance	Б	V <sub>GS</sub> =10V, I <sub>D</sub> =10A	-	5.4	7.0	mΩ
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =4.5A	-	7.0	12	
Forward Transconductance	<b>g</b> FS	$V_{DS}$ =5 $V$ , $I_D$ =24A	20	-	-	S
Dynamic Characteristics (Note4)			1	ı		•
Input Capacitance	C <sub>lss</sub>	\\ 45\\\\ 0\\	-	2060	-	PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =15V,V <sub>GS</sub> =0V,	-	320	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHz	-	235	-	PF
Switching Characteristics (Note 4)			•	•		•
Turn-on Delay Time	t <sub>d(on)</sub>		-	20	-	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =10 $V$ , $I_D$ =30 $A$	-	15	-	nS
Turn-Off Delay Time	$t_{d(off)}$	$V_{GS}$ =10 $V$ , $R_{GEN}$ =2.7 $\Omega$	-	60	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	10	-	nS
Total Gate Charge	Qg	V -40VI -20A	-	51	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =10V, $I_{D}$ =30A, $V_{GS}$ =10V	-	14	-	nC
Gate-Drain Charge	$Q_{gd}$	V <sub>GS</sub> =10V	-	11	-	nC
Drain-Source Diode Characteristics				•		
Diode Forward Voltage (Note 3)	$V_{SD}$	V <sub>GS</sub> =0V,I <sub>S</sub> =24A	-	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	80	Α
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, IF = 80A	-	32	50	nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	12	20	nC

#### Notes:

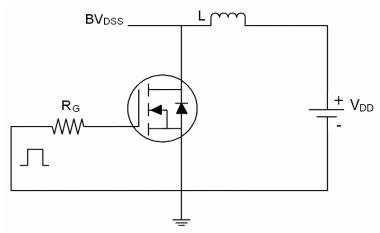
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- 3. Pulse Test: Pulse Width ≤  $300\mu s$ , Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- 5. EAS condition: Tj=25  $^{\circ}\text{C}$  ,V  $_{DD}$  =15V,V  $_{G}$  =10V,L=0.5mH, Rg=25  $\Omega$

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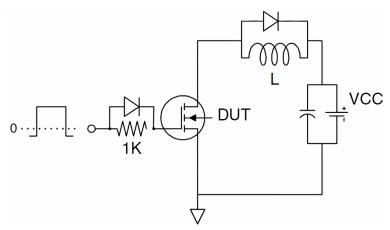


## **Test Circuit**

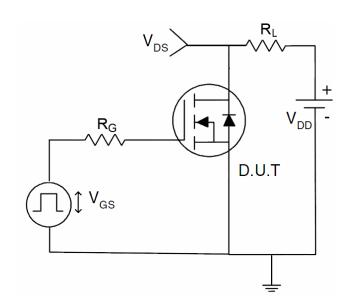
# 1) E<sub>AS</sub> Test Circuits



# 2) Gate Charge Test Circuit:



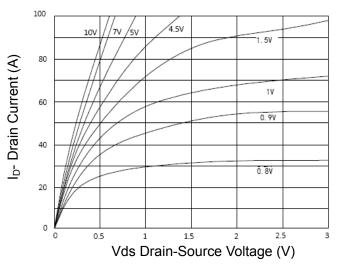
## 3) Switch Time Test Circuit:



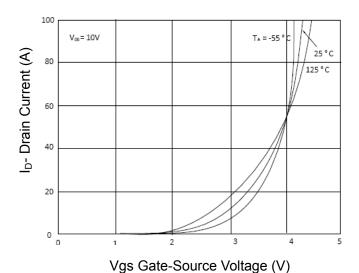
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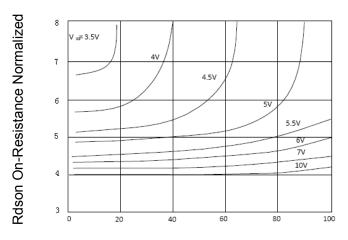
## **Typical Electrical and Thermal Characteristics (Curves)**



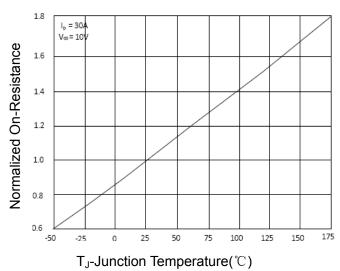
**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 



I<sub>D</sub>- Drain Current (A) **Figure 3 Rdson- Drain Current** 



**Figure 4 Rdson-Junction Temperature** 

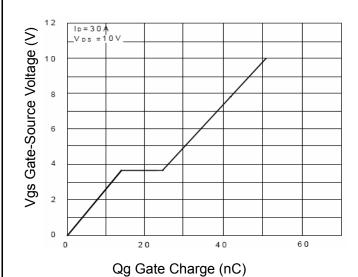


Figure 5 Gate Charge

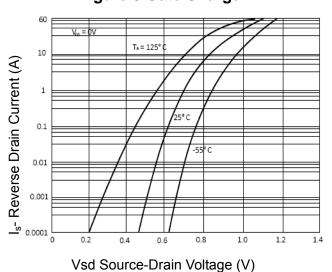
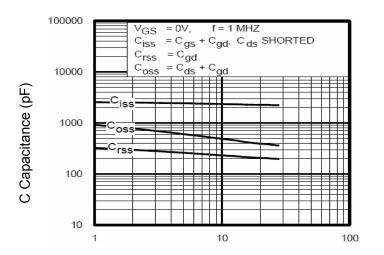


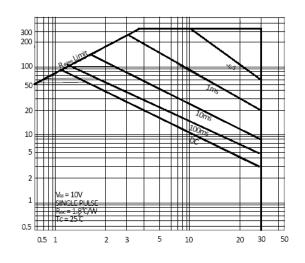
Figure 6 Source- Drain Diode Forward





Vds Drain-Source Voltage (V)

Figure 7 Capacitance vs Vds

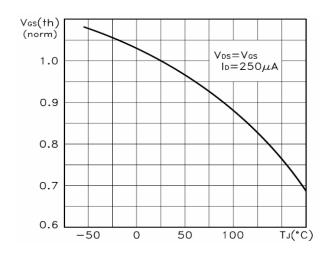


lp- Drain Current (A)

Vds Drain-Source Voltage (V) **Figure 8 Safe Operation Area** 

BVDSS V<sub>GS</sub>=0 (norm)  $l_{D}=250\mu A$ 1.2 Normalized BVdss 1.1 1.0 0.9 8.0 50 100 TJ(°C)

 $T_J$ -Junction Temperature( $^{\circ}$ C) Figure 9 BV<sub>DSS</sub> vs Junction Temperature



 $T_J$ -Junction Temperature( $^{\circ}$ C) Figure 10 V<sub>GS(th)</sub> vs Junction Temperature

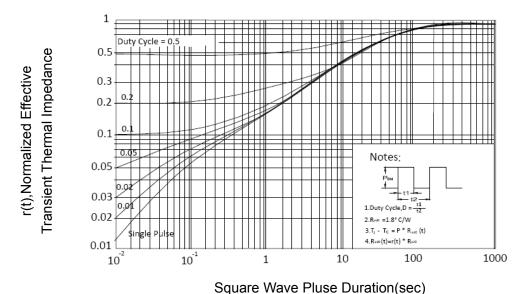
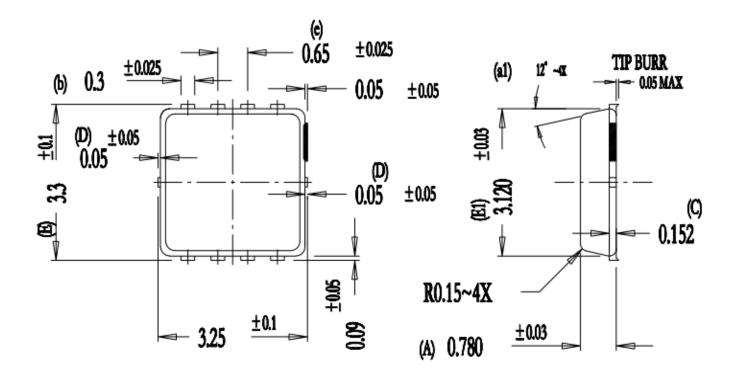


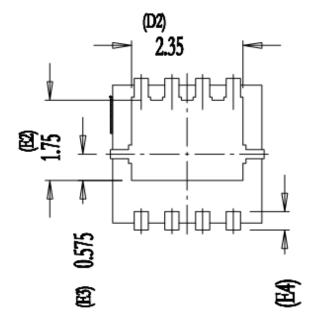
Figure 11 Normalized Maximum Transient Thermal Impedance

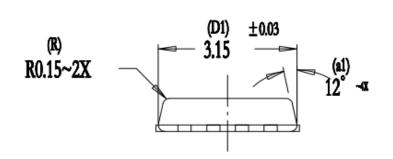
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# **DFN3.3\*3.3 Package Information**







en mor	MILLIMETER			
SYMBOL	MON	NOM	MAX	
Λ	0.75	0.78	0.81	
A1				
Ь	0.297	0.3	0.35	
c	_	0.152	-	
D	0.00	0.05	0.1	
D1	3.12	3.15	3.18	
D2	_	2.35		
E	3.2	33	3.4	
E1	3.09	3.12	3.15	
R2	_	1.75		
E3	_	0.575		
B4				
R	_	0.15		
e	0.65BSC			
al'	_	12'		



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